

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/631,812	TAKAHASHI ET AL.
	<b>Examiner</b> Hoai V. Ho	<b>Art Unit</b> 2827

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	185.29	4/9/05	1072
	185.03		
	185.28		